Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
1	IS&R	2	("6724210").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:02		
2	IS&R	2	("6397361").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:56		
3	BRS	3	chip-to-package with connect$5 with test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:18		
4	BRS	3	chip-to-package with test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:57		
5	BRS	6	chip-to-package with I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:58		
6	BRS	31	chip-to-package and I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 11:57		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
7 BRS	4	chip-to-package and I/O and transition	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:01		
8 BRS	2	chip-to-package with connection with I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:02		
9 BRS	4	chip-to-package with connection and I/O with semiconductor$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:02		
10 BRS	84	chip-to-package	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:21		
11 BRS	2	324/$.ccls. and chip-to-package and test$3 with semiconductor$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:05		
12 BRS	4	chip-to-package and test$3 with semiconductor$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:06		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
13	BRS	337	test$3 with semiconductor$1 with i/o	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:08		
14	BRS	26	test$3 with semiconductor$1 with i/o with connection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:21		
15	BRS	4	chip-to-package and test$3 with semiconductor$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:23		
16	BRS	17	chip-to-package and test$3 with (wafer$1 or semiconductor$1 or integrated adj circuit$1 or Ic$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:24		
17	BRS	8	chip-to-package and test$3 with (wafer$1 or semiconductor$1 or integrated adj circuit$1 or Ic$1) and I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 17:24		
18	BRS	1	"6556621".PN.	USPAT	2004/06/16 09:05		
19	BRS	1	"6115113".PN.	USPAT	2004/06/16 09:05		
20	BRS	1	"5418820".PN.	USPAT	2004/06/16 09:06		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
21 BRS	8	test$3 with (semiconductor adj chip) with (semiconductor adj package) with connect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:27		
22 BRS	43230	test$3 with semiconductor chip with package with connect$5 with I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:28		
23 BRS	8	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) with chip with package with connect$5 with I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:33		
24 BRS	23	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) with chip with package with connect$5 with (input/output or I/O)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:03		
25 BRS	26	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) with chip$1 with package$1 with connect$5 with (input/output or I/O)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:45		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
26 BRS	3	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) with chip$1 with package$1 with connect$5 with (input/output or I/O) and response with time	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:39		
27 BRS	8	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and chip$1 with package$1 with connect$5 with (input/output or I/O) and response with time	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:39		
28 BRS	152	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and chip$1 with package$1 with connect$5 with (input/output or I/O)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:47		
29 BRS	7	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and chip$1 with package$1 with connect$5 with (input/output or I/O) and transition with signal$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:51		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
30	BRS	7	6397361.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:54		
31	BRS	7	6397361.uref. and (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 09:54		
32	BRS	80	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and I/O with receiver with driver	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:16		
33	BRS	7	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and I/O with receiver with driver and perform$3 with connect$5 with (I/O or input/output)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:11		
34	BRS	2	6057698.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:11		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
35	BRS	36	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and I/O with receiver with driver with connect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 12:05		
36	BRS	26	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and I/O with receiver with driver with connect$5 and respons$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:37		
37	BRS	742	RC adj1 constant	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:36		
38	BRS	2	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and I/O with receiver with driver with connect$5 and RC adj1 constant	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:37		
39	BRS	2	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) and RC adj1 constant with I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 10:38		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
40	BRS	27	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) or adj1 constant	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 11:45		
41	IS&R	2	("6058496").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 11:03		
42	IS&R	2	("6348811").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 11:45		
43	BRS	2	chip-to-package with connection with (i/o or input/output)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 11:58		
44	BRS	21	chip-to-package and connection with (i/o or input/output)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 12:05		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
45 BRS	11	test$3 with (wafer$1 or IC$1 or (integrated adj circuit$1) or semiconductor$1) or with receiver with driver with connect$5 and chip$1 with (package$1 or die or substrate) and I/O	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:39		
46 BRS	207	detect$3 with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:40		
47 BRS	31	detect$3 with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and compar$4 with (threshold$1 or predetermined)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:42		
48 BRS	55	detect$3 with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:42		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
49 BRS	212	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:42		
50 BRS	162	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:43		
51 BRS	16	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2) and fixture	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:44		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
52	BRS	5196	324/713,763,765,538,711.cc ls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:50		
53	BRS	773	702/117,118.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:51		
54	BRS	25	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2) and package$1 with chip$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:09		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
55 BRS	4	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2) and package$1 with chip$1 and driver$1 with receiver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/16 14:56		
56 BRS	2	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and driver with sensitive with capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:11		
57 BRS	5	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and sensitive with capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:14		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
58	BRS	5	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and driver with capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:19		
59	BRS	7	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and weak with driver	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:42		
60	BRS	0	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or (integrated adj circuit$1)) and driver with deliver$3 with (current or capacit$4 or load$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:41		
61	BRS	8	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and weak$3 with driver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 09:45		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
62	BRS	31	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and delay with driver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:11		
63	BRS	5	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and delay with driver$1 with (current$1 or capacit$4 or load$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:43		
64	BRS	1	"6480817".PN.	USPAT	2004/06/17 10:10		
65	BRS	1	"6292766".PN.	USPAT	2004/06/17 10:10		
66	BRS	0	6662352.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:11		
67	BRS	8	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and additional with imped$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:48		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
68 BRS	37	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and imped$4 with connection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:49		
69 BRS	4	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and driver with imped$4 with connection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 10:49		
70 BRS	2	"20020169588"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 12:30		
71 BRS	2	"20020079926"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 12:31		
72 BRS	2	"20020046374"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 12:31		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti on
73	IS&R 2	("5509019").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 12:35		